

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

LIST OF PRIOR ART CITED BY APPLICANT

(PTO-1449)

ATTY. DOCKET NO.
K-195B

APPLN. SERIAL NO.
10/669,445

APPLICANT(S)
Jae K. KIM et al.

FILING DATE
September 25, 2003

GROUP
3726

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
EC	2,531,225	11/1950	LE TOURNEAU			
	2,656,702	10/1953	CHAPIN			
	3,194,032	7/1965	VON BRIMER			
	4,686,399	8/1987	IMORI ET AL.			
	5,966,379	10/1999	PHILLIPS ET AL.			
EC	6,049,930	4/2000	HISANO ET AL.			

U.S. PATENT APPLICATION PUBLICATIONS

	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	

U.S. PATENT APPLICATIONS

	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
EC	2,006,836	5/1979	UK				
I	2,202,867	10/1988	UK				
EC	95/17543	6/1995	WIPO				


OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

EXAMINER

Eric [Signature]

DATE CONSIDERED

6/5/06

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				APPLICANT(S) Jae K. KIM et al.			
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U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE	
EC	5,586,455	12/1996	IMAI				
EC	6,006,553	12/1999	LEE ET AL.				
EC	6,023,839	2/2000	KINOSHITA				
EC	6,339,275	1/2002	KATAGIRI				
EC	6,661,550	12/2003	KONNO ET AL.				
U.S. PATENT APPLICATION PUBLICATIONS							
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS		
U.S. PATENT APPLICATIONS							
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS		
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
EC	31 05 318	8/1982	GERMANY			Abst	
EC	36 34 214	4/1998	GERMANY			Abst	
EC	36 14 703	11/1986	GERMANY			Abst	
EC	60-5197	1/1985	JAPAN				X
EC	2,189,511	10/1987	UK				
EC	2,261,881	6/1993	UK			Abst	
EC	0 198 554	10/1986	EPO				
EC	0 354 158	2/1990	EPO				
EC	0 374 519	6/1990	EPO				
EC	2,272,913	6/1994	UK				
EC	2,322,240	6/1998	UK				
OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)							
EXAMINER 				DATE CONSIDERED 9/5/2006			

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U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
EC	5,528,092	6/1996	OHTA			
EC	6,341,507	1/2002	RODE ET AL.			

U.S. PATENT APPLICATION PUBLICATIONS

	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	

U.S. PATENT APPLICATIONS

	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
EC	7-68086	3/1995	JAPAN			Abst	

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DATE CONSIDERED

6/5/2006